

NS7000 Series

NS7160W

- Best handler for multi-site testing of integrated logic/memory devices
- Capable of 16-site simultaneous testing

NS7080W

- Expanded socket area enables docking to a wide variety of socket layouts



Feature

1. Flexible socket layout
 - Wide range of available socket layouts including "square 4-site"
2. Outstanding basic functions
 - High throughput of 7300 UPH (units per hour) and index times from 0.36 sec.
 - Steady temperature due to use of a chamber in the test site
3. Compatible with a wide range of device types (small, thin, etc.)
 - Damage-free testing of ultra thin devices in soft contact mode
 - Capable of testing small devices such as MLPTM and MLFTM
 - Capable of testing CMOS image sensors and RF devices

4. Contact force controlled by electro-pneumatic regulator
5. Auto teaching
 - Capable of auto teaching using auto-teaching jigs
6. ESD (electrostatic discharge) reduction
 - Can provide required level of ESD protection
7. Multi-lingual operation screen
 - Multi-language support available for operation screens
8. Side-docking test head
9. CE marking
10. Options
 - One-touch Lock socket Plate
 - High Contact Pressure
 - Motor Rotator Hand
 - Wide Hot Plate
 - Cross Sensors
 - Different Tray Handling for Loading/Unloading

Main specifications

	NS-7000/NS-7080	NS-7080W/NS-7160W
Device type	QFP, TSOP, CSP, BGA, QFN, PLCC, LGA, PGA, RF Device, CMOS Image sensor	
	Min. 3x3 to Max. 50x50 (Lead pitch: 0.4 mm or more) ^{*1}	
Test mode	8-site (4x2) ^{*2} Square 4-site (2x2) In-Line 4-site(4x1) 2-site Busy Shuttle (single)	16-site (8x2) ^{*3} 8-site (4x2) Square 4-site (2x2) In-Line 4-site(4x1) 2-site Busy Shuttle (single)
Index time	0.36 sec	
Throughput	Max. 7,300 unit per hour	
Temperature accuracy	+50degC to + 90degC ±2degC ^{*3}	
	+90degC to +130degC ±3degC ^{*3}	
Dimension (mm)	1,640(W) x 1,580(D) x 1860(H) ^{*4}	1,800(W) x 1,580(D) x 1860(H) ^{*4}
Weight	Approx. 1,120Kg	Approx. 1,190kg

^{*1} Depends on the socket size and socket pitch.

^{*2} For NS-7080

^{*3} For NS-7160